BYV32EB-200

Dual rugged ultrafast rectifier diode, 20 A, 200 V Rev. 04 — 2 March 2009

Product data sheet

Product profile 1.

1.1 General description

Ultrafast dual epitaxial rectifier diode in a SOT404 (D2PAK) surface-mountable plastic package.

1.2 Features and benefits

- High reverse voltage surge capability
- High thermal cycling performance
- Low thermal resistance

- Soft recovery characteristic minimizes power consuming oscillations
- Surface-mountable package
- Very low on-state loss

1.3 Applications

Output rectifiers in high-frequency switched-mode power supplies

1.4 Quick reference data

Table 1. **Quick reference**

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{RRM}	repetitive peak reverse voltage		-	-	200	V
I _{O(AV)}	average output current	square-wave pulse; δ = 0.5; $T_{mb} \le 115$ °C; both diodes conducting; see <u>Figure 1</u> ; see <u>Figure 2</u>	-	-	20	Α
I _{RRM}	repetitive peak reverse current	$t_p = 2 \ \mu s; \ \delta = 0.001$	-	-	0.2	Α
V _{ESD}	electrostatic discharge voltage	HBM; C = 250 pF; R = 1.5 k Ω ; all pins	-	-	8	kV
Dynamic	characteristics					
t _{rr}	reverse recovery time	$I_F = 1 \text{ A}$; $V_R = 30 \text{ V}$; $dI_F/dt = 100 \text{ A/}\mu\text{s}$; $T_j = 25 \text{ °C}$; ramp recovery; see Figure 5	-	20	25	ns
		I_R = 1 A; I_F = 0.5 A; T_j = 25 °C; measured at reverse current = 0.25 A; step recovery; see Figure 6	-	10	20	ns
Static ch	aracteristics					
V _F	forward voltage	$I_F = 8 \text{ A}$; $T_j = 150 \text{ °C}$; see Figure 4	-	0.72	0.85	V





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Dual rugged ultrafast rectifier diode, 20 A, 200 V

Pinning information

Table 2. **Pinning information**

		,			
Pin	Symbol	Description		Simplified outline	Graphic symbol
1	A1	anode 1			
2	K	cathode	[1]	mb	A1
3	A2	anode 2			<u> </u>
	K mounting base; cathode				sym125
				SOT404 (D2PAK)	

[1] it is not possible to make a connection to pin 2 of the SOT404 package

Ordering information

Table 3. **Ordering information**

Product data sheet

Type number Package				
	Name	Description	Version	
BYV32EB-200	D2PAK	plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped)	SOT404	

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{RRM}	repetitive peak reverse voltage		-	200	V
V_{RWM}	crest working reverse voltage		-	200	V
V_R	reverse voltage	DC	-	200	V
I _{O(AV)}	average output current	square-wave pulse; δ = 0.5; $T_{mb} \le 115$ °C; both diodes conducting; see Figure 1; see Figure 2	-	20	Α
I _{FRM}	repetitive peak forward current	δ = 0.5; t_p = 25 μ s; T_{mb} ≤ 115 °C; per diode	-	20	Α
I _{FSM}	non-repetitive peak forward current	t_p = 8.3 ms; sine-wave pulse; $T_{j(init)}$ = 25 °C; per diode	-	137	Α
		t_p = 10 ms; sine-wave pulse; $T_{j(init)}$ = 25 °C; per diode	-	125	Α
I _{RRM}	repetitive peak reverse current	$\delta = 0.001$; $t_p = 2 \mu s$	-	0.2	Α
I _{RSM}	non-repetitive peak reverse current	$t_p = 100 \ \mu s$	-	0.2	Α
T _{stg}	storage temperature		-40	150	°C
Tj	junction temperature		-	150	°C
V _{ESD}	electrostatic discharge voltage	HBM; C = 250 pF; R = 1.5 k Ω ; all pins	-	8	kV

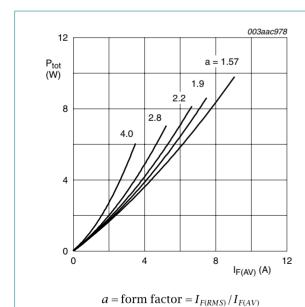


Fig 1. Forward power dissipation as a function of average forward current; sinusoidal waveform; maximum values

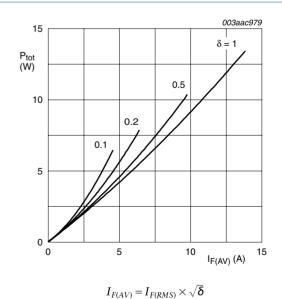


Fig 2. Forward power dissipation as a function of average forward current; square waveform; maximum values

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5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting	with heatsink compound; both diodes conducting	-	-	1.6	K/W
	base	with heatsink compound; per diode; see Figure 3	-	-	2.4	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient	minimum footprint FR4 board	-	50	-	K/W

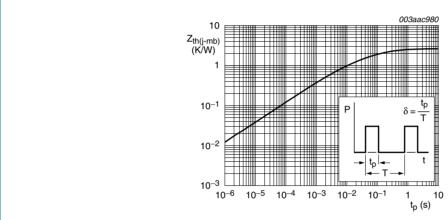
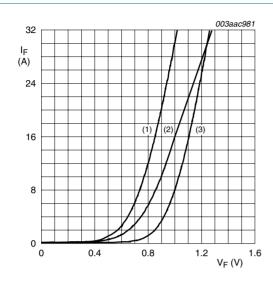


Fig 3. Transient thermal impedance from junction to mounting base as a function of pulse width

6. Characteristics

Table 6. Characteristics

Parameter					
i didilictel	Conditions	Min	Тур	Max	Unit
aracteristics					
forward voltage	I _F = 8 A; T _j = 150 °C; see <u>Figure 4</u>	-	0.72	0.85	V
	I _F = 20 A; T _j = 25 °C	-	1	1.15	V
reverse current	V _R = 200 V; T _j = 25 °C	-	6	30	μΑ
	V _R = 200 V; T _j = 100 °C	-	0.2	0.6	mA
characteristics					
recovered charge	$I_F = 2 \text{ A}; V_R = 30 \text{ V}; dI_F/dt = 20 \text{ A/}\mu\text{s}$	-	8	12.5	nC
reverse recovery time	$I_F = 1 \text{ A}$; $V_R = 30 \text{ V}$; $dI_F/dt = 100 \text{ A/}\mu\text{s}$; ramp recovery; $T_j = 25 \text{ °C}$; see Figure 5	-	20	25	ns
	I_F = 0.5 A; I_R = 1 A; measured at reverse current = 0.25 A; step recovery; T_j = 25 °C; see Figure 6	-	10	20	ns
forward recovery voltage	$I_F = 1 \text{ A}$; $dI_F/dt = 10 \text{ A/}\mu\text{s}$; see Figure 7	-	-	1	V
	reverse current characteristics recovered charge reverse recovery time	$I_F = 8 \text{ A}; \ T_j = 150 \text{ °C}; \ \text{see} \ \frac{\text{Figure} \ 4}{\text{I}_F = 20 \ \text{A}; \ T_j = 25 \text{ °C}}$ reverse current $V_R = 200 \text{ V}; \ T_j = 25 \text{ °C}$ $V_R = 200 \text{ V}; \ T_j = 100 \text{ °C}$ $Characteristics$ recovered charge $I_F = 2 \text{ A}; \ V_R = 30 \text{ V}; \ dI_F/dt = 20 \text{ A/}\mu\text{s}$ reverse recovery time $I_F = 1 \text{ A}; \ V_R = 30 \text{ V}; \ dI_F/dt = 100 \text{ A/}\mu\text{s};$ ramp recovery; $T_j = 25 \text{ °C}; \text{ see} \ \frac{\text{Figure} \ 5}{\text{I}_F = 0.5 \ \text{A}}; \ I_R = 1 \text{ A}; \ \text{measured at reverse}$ current = 0.25 A; step recovery; $T_j = 25 \text{ °C};$ see $\frac{\text{Figure} \ 6}{\text{Figure} \ 6}$ forward recovery $I_F = 1 \text{ A}; \ dI_F/dt = 10 \text{ A/}\mu\text{s}; \text{ see} \ \frac{\text{Figure} \ 7}{\text{Figure} \ 7}$	$I_F = 8 \text{ A}; \ T_j = 150 \text{ °C}; \ \text{see } \frac{\text{Figure 4}}{\text{Igensure 200 N}} - \frac{1}{\text{Igensure 200 N}; \ T_j = 25 \text{ °C}} - \frac{1}{\text{Igensure 200 N}; \ T_j = 25 \text{ °C}} - \frac{1}{\text{Igensure 200 N}; \ T_j = 100 \text{ °C}} - \frac{1}{\text{Igensure 200 N}; \ T_j = 100 \text{ °C}} - \frac{1}{\text{Igensure 200 N}; \ T_j = 100 \text{ °C}} - \frac{1}{\text{Igensure 200 N}; \ T_j = 100 \text{ °C}} - \frac{1}{\text{Igensure 200 N}; \ T_j = 20 \text{ N/gs}} - \frac{1}{\text{Igensure 200 N}; \ T_j = 25 \text{ °C}; \ See } \frac{1}{\text{Figure 30 N}; \ T_j = 25 \text{ °C}; \ See } \frac{1}{\text{Figure 30 N}; \ T_j = 25 \text{ °C}; \ See } \frac{1}{\text{Figure 30 N}; \ T_j = 25 \text{ °C}; \ See } \frac{1}{\text{Figure 30 N}; \ T_j = 25 \text{ °C}; \ See } \frac{1}{\text{Figure 30 N}; \ T_j = 25 \text{ °C}; \ See } \frac{1}{\text{Figure 30 N}; \ T_j = 25 \text{ °C}; \ See } \frac{1}{\text{Figure 30 N}; \ T_j = 25 \text{ °C}; \ See } \frac{1}{\text{Figure 30 N}; \ T_j = 25 \text{ °C}; \ See } \frac{1}{\text{Figure 30 N}; \ T_j = 25 \text{ °C}; \ See } \frac{1}{\text{Figure 30 N}; \ T_j = 25 \text{ °C}; \ See } \frac{1}{\text{Figure 30 N}; \ T_j = 25 \text{ °C}; \ See } \frac{1}{\text{Figure 30 N}; \ T_j = 25 \text{ °C}; \ See } \frac{1}{\text{Figure 30 N}; \ T_j = 25 \text{ °C}; \ See } \frac{1}{\text{Figure 30 N}; \ T_j = 25 \text{ °C}; \ See } \frac{1}{\text{Figure 30 N}; \ T_j = 25 \text{ °C}; \ See } \frac{1}{\text{Figure 30 N}; \ T_j = 25 \text{ °C}; \ T_j = 25 \text{ °C}; \ See } \frac{1}{\text{Figure 30 N}; \ T_j = 25 \text{ °C}; \ See } \frac{1}{\text{Figure 30 N}; \ T_j = 25 \text{ °C}; \ T_j = 25 \text{ °C}; \ See } \frac{1}{\text{Figure 30 N}; \ T_j = 25 \text{ °C}; \ T$		



- (1) $T_j = 150$ °C; typical values
- (2) $T_j = 150$ °C; maximum values
- (3) $T_j = 25$ °C; maximum values

Fig 4. Forward current as a function of forward voltage

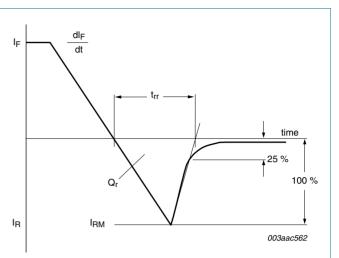


Fig 5. Reverse recovery definitions; ramp recovery

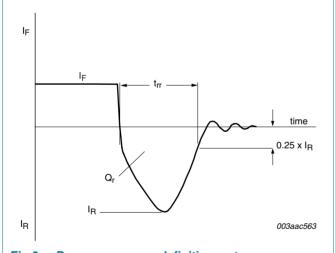
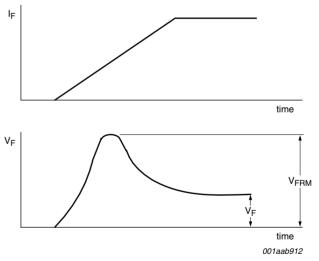


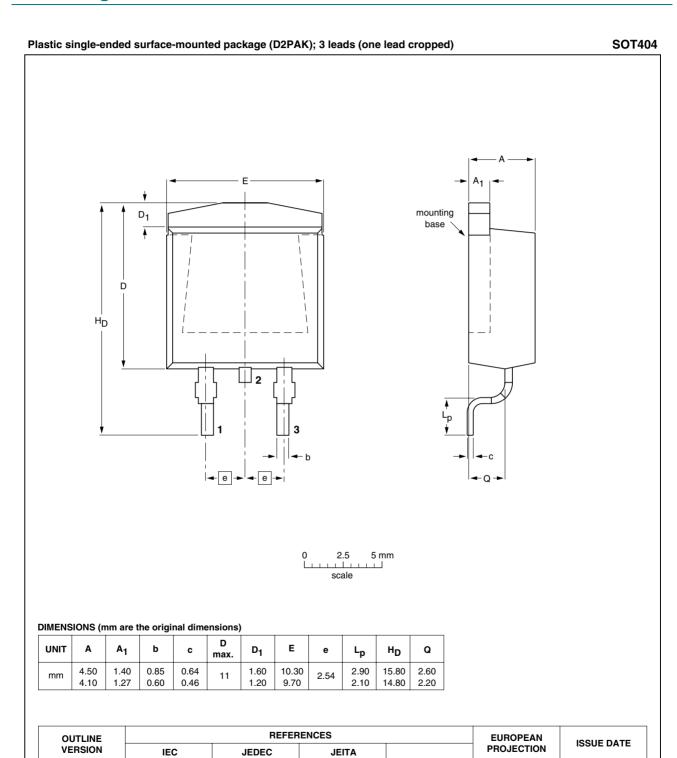
Fig 6. Reverse recovery definitions; step recovery



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Fig 7. Forward recovery definitions

Package outline



Package outline SOT404 (D2PAK)

SOT404

05-02-11

06-03-16



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Dual rugged ultrafast rectifier diode, 20 A, 200 V

8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BYV32EB-200_4	20090302	Product data sheet	-	BYV32E_SERIES_3
Modifications:		of this data sheet has been of NXP Semiconductors.	n redesigned to comply w	ith the new identity
	 Legal texts 	have been adapted to the	new company name whe	re appropriate.
	 Package or 	utline updated.		
	 Type numb 	er BYV32EB-200 separate	d from data sheet BYV32	E_SERIES_3
BYV32E_SERIES_3	20010301	Product specification	-	BYV32E_SERIES_2
BYV32E_SERIES_2	19980701	Product specification	-	BYV32EB_SERIES_1
BYV32EB_SERIES_1	19960801	Product specification	-	-

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9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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